

Notice of References Cited	Application/Control No. 10/518,948	Applicant(s)/Patent Under Reexamination DOU ET AL.	
	Examiner Mark Kopec	Art Unit 1796	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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